

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

First Named
Inventor : David W. Duquette

Appln. No. : 09/767,199

Filed : January 22, 2003

For : IMPROVED LASER ALIGN SENSOR
WITH SEQUENCING LIGHT
SOURCES

Docket No.: C34.12-0021



01-17-02

JP 2877
#7
BT

Group Art Unit: 2877

Examiner:

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
Washington, D.C. 20231

I HEREBY CERTIFY THAT THIS PAPER IS BEING
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10th day of January, 2003.


PATENT ATTORNEY

Sir:

The patents or publications listed on the enclosed PTO Form-1449 are submitted pursuant to 37 C.F.R. § 1.97. Copies of the patents or publications cited are enclosed.

The Director is authorized to charge any fee deficiency required by this paper or credit any overpayment to Deposit Account No. 23-1123.

Respectfully submitted,

WESTMAN, CHAMPLIN & KELLY, P.A.

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FORM PTO-1449

Atty. Docket No.: C34.12-0021

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LIST OF PATENTS AND PUBLICATIONS FOR
APPLICANT'S INFORMATION
DISCLOSURE STATEMENT

First Named Inventor:

David W. Duquette

Filing Date

January 22, 2001

Group Art:

2877

U. S. PATENT DOCUMENTS

Examiner Initial	Document No.	Date	Name	Class	Sub Class	Filing Date If Appropriate
AA	4,974,010	11/27/90	Cleveland et al.	354	403	
AB	5,377,405	01/03/95	Sakurai et al.	29	833	
AC	5,491,888	02/20/96	Sakurai et al.	29	832	
AD	5,815,272	09/29/98	Harding	356	375	
AE	5,818,061	10/06/98	Stern et al.	250	550.29	
AF	5,897,611	04/27/99	Case et al.	702	150	
AG	6,028,671	02/22/00	Svetkoff et al.	356	368	
AH						
AI						
AJ						

FOREIGN PATENT DOCUMENTS

	Document No.	Date	Country	Class	Sub Class	Translation Yes No
AK	8-111598	4/30/96	Japan			X (Abstract)
AL	9-214198	8/15/97	Japan			X
AM						
AN						

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

AQ	
AP	
AQ	
AR	

EXAMINER:

DATE CONSIDERED:

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

2001-01-22
JAN 22 2001
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WILMINGTON, DE 19801-3514